

Powder Diffraction

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Powder Diffraction An international journal of materials characterization

A detailed photograph of a Siemens D 500 X-ray diffractometer. The machine is a complex piece of industrial equipment with a large, circular goniometer in the center. The goniometer has several concentric rings and various mechanical components. A sample stage is visible in the center of the goniometer. The lighting is dramatic, with a strong blue and green glow emanating from the machine, highlighting its metallic surfaces and intricate details. The background is dark, making the machine stand out.

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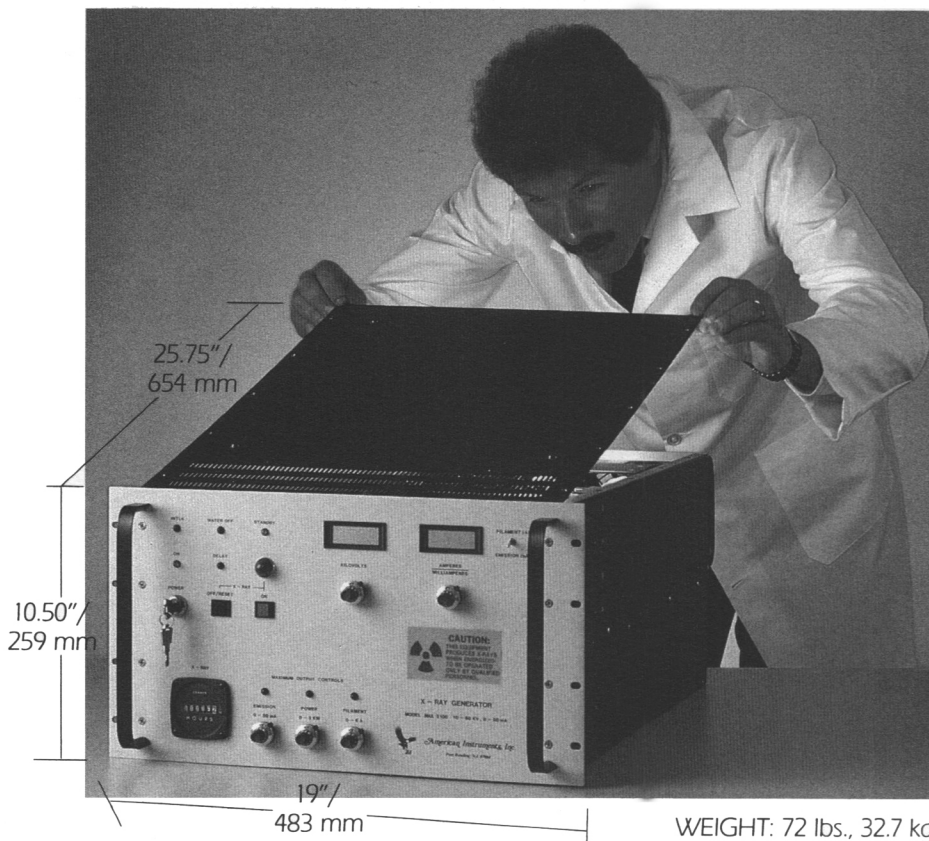
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JCPDS-International Centre
for Diffraction Data
1601 Park Lane
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Curtin University
Dept. of Applied Physics
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Editor for New Diffraction Data

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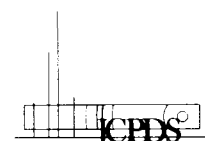
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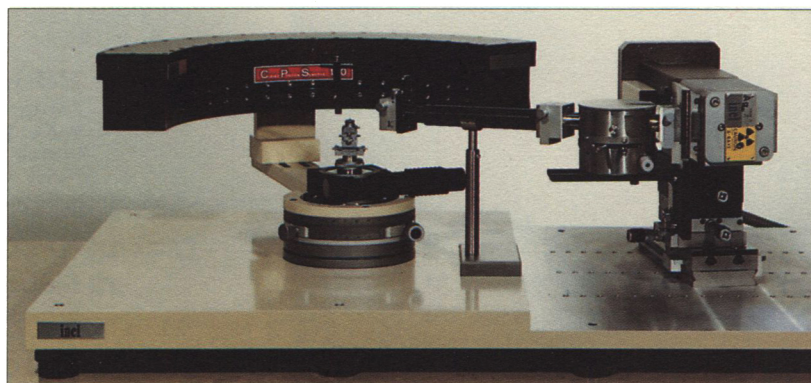
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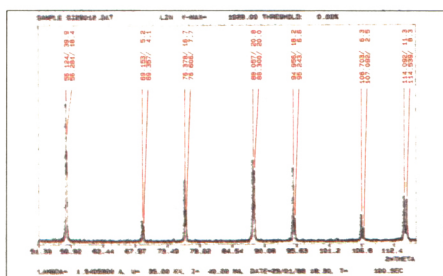
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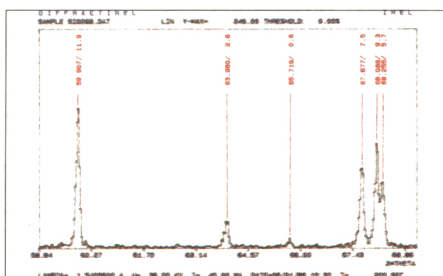
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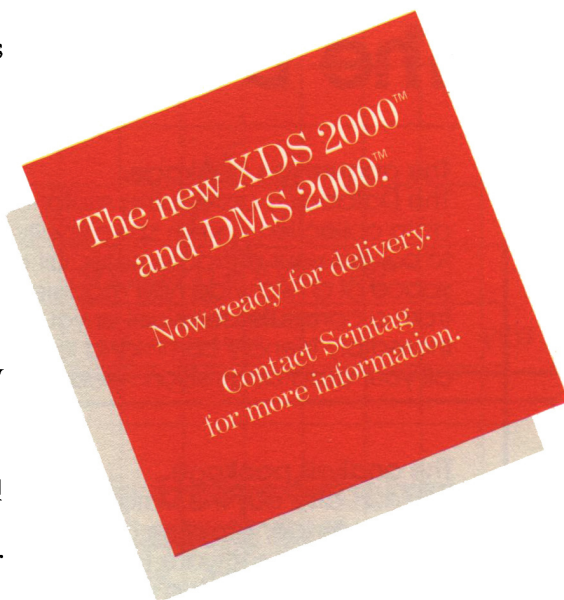
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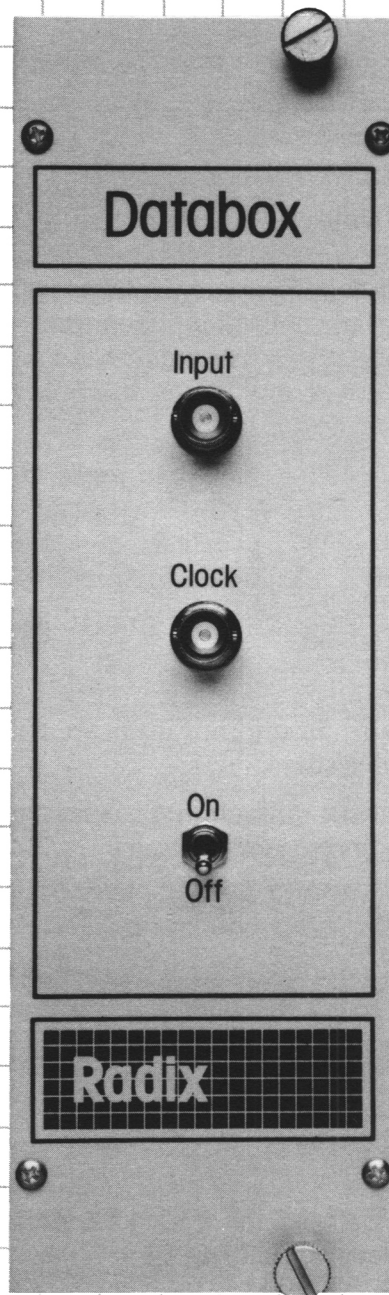
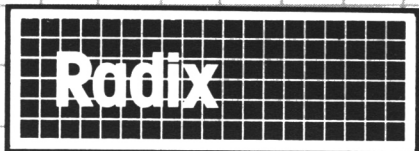
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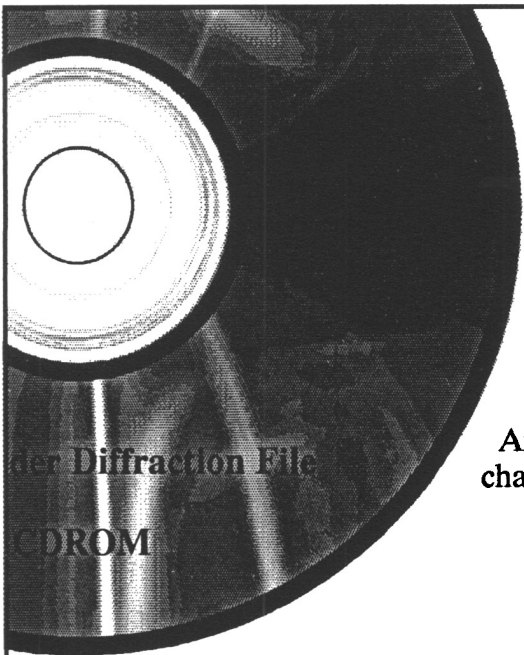
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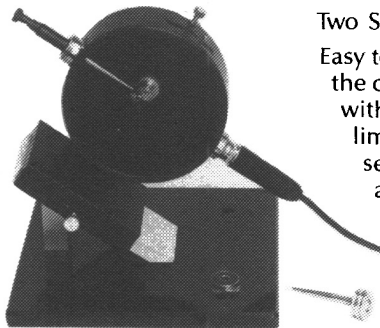


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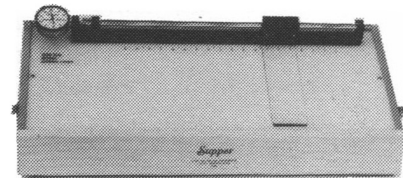
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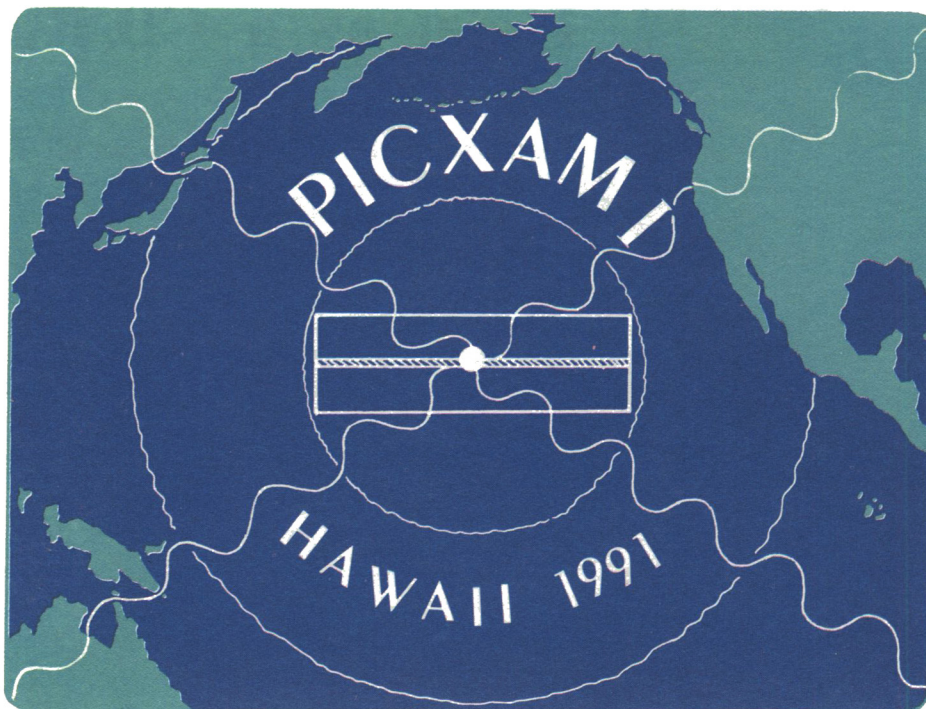
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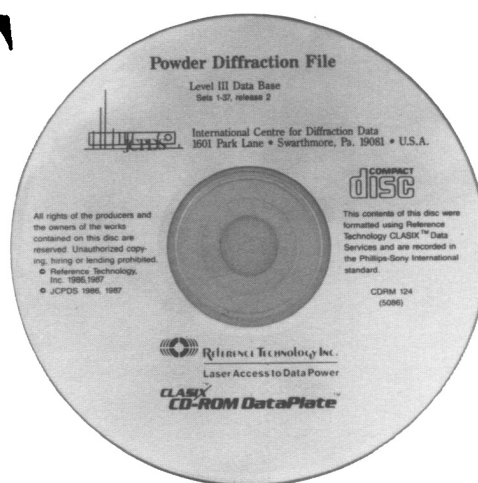
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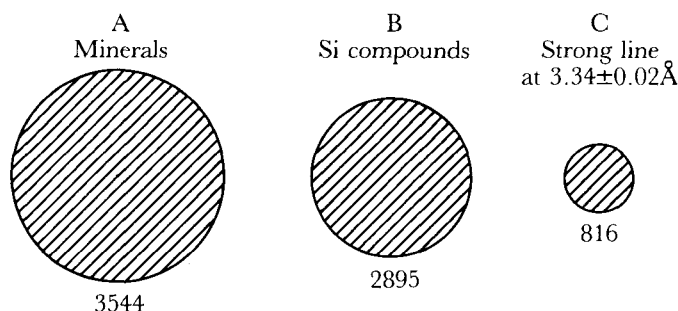
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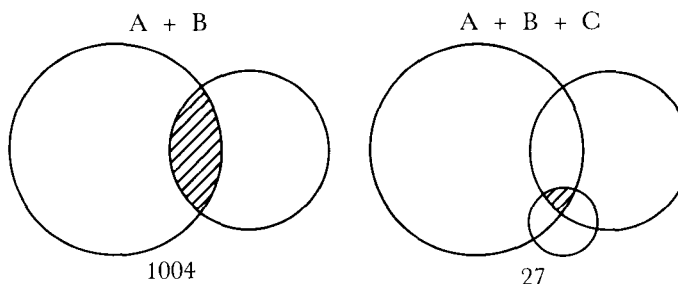
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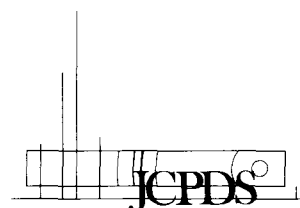
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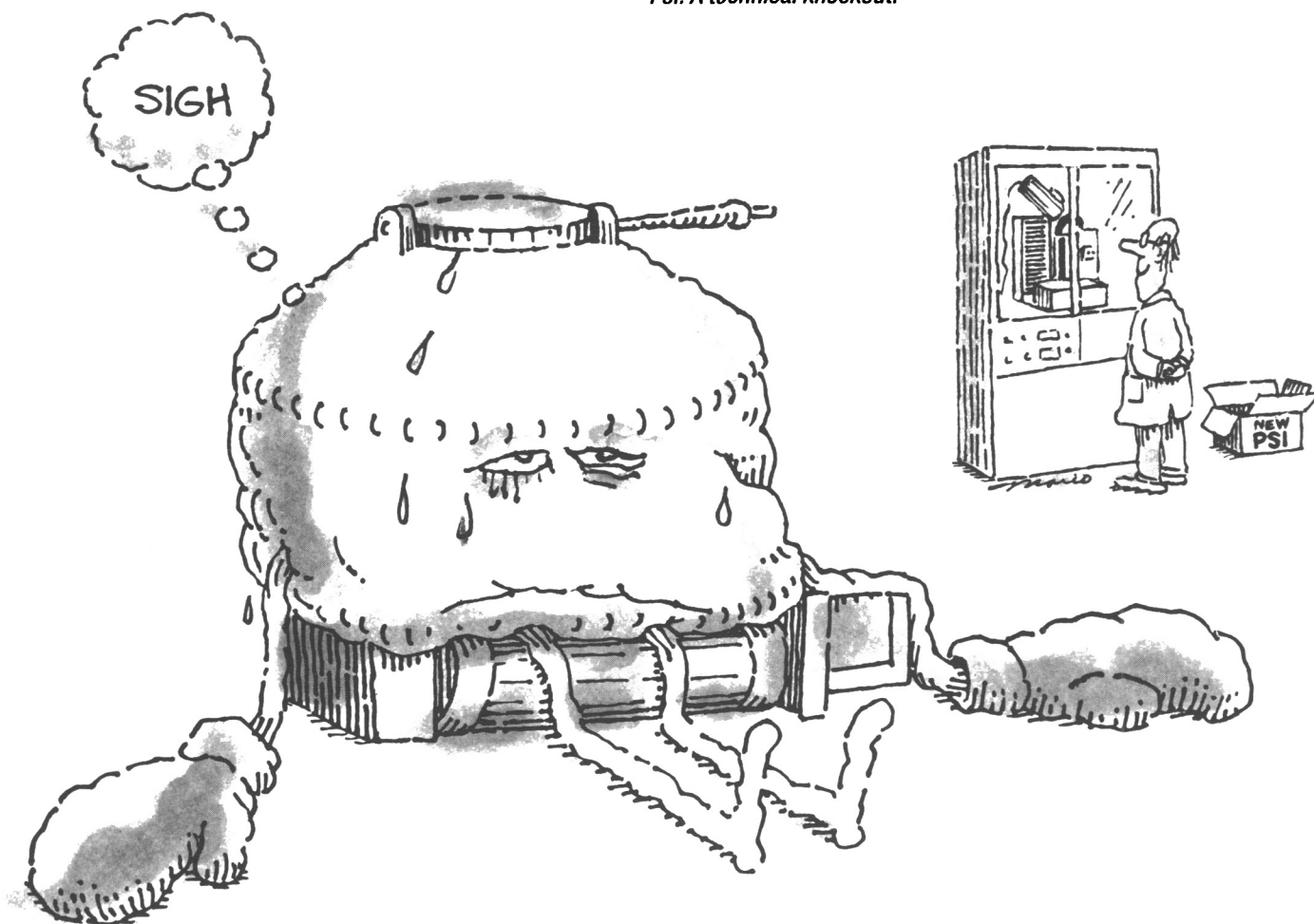
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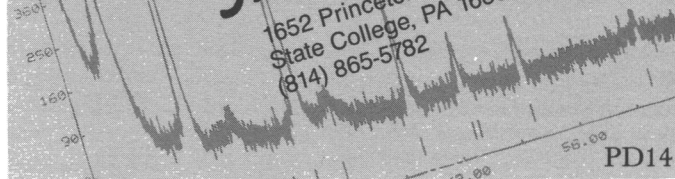
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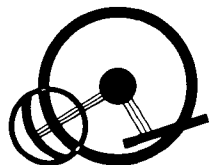
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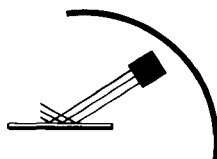
- Fundamentals

Session II June 12-16

- Advances, Mathematical & Computer Methods

Session III August 28-September 1

- Mathematical & Computer Methods



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Session I June 19-23

- Fundamentals

Session II June 26-30

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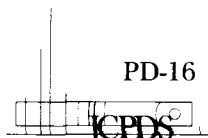
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1601 Park Lane, Swarthmore, PA 19081
USA (215) 328-9400 Telex: 847170



PD-16

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Set 38 1988-1989

Powder Diffraction File

Set 38 Pattern Profile:

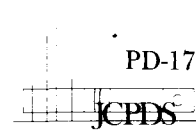
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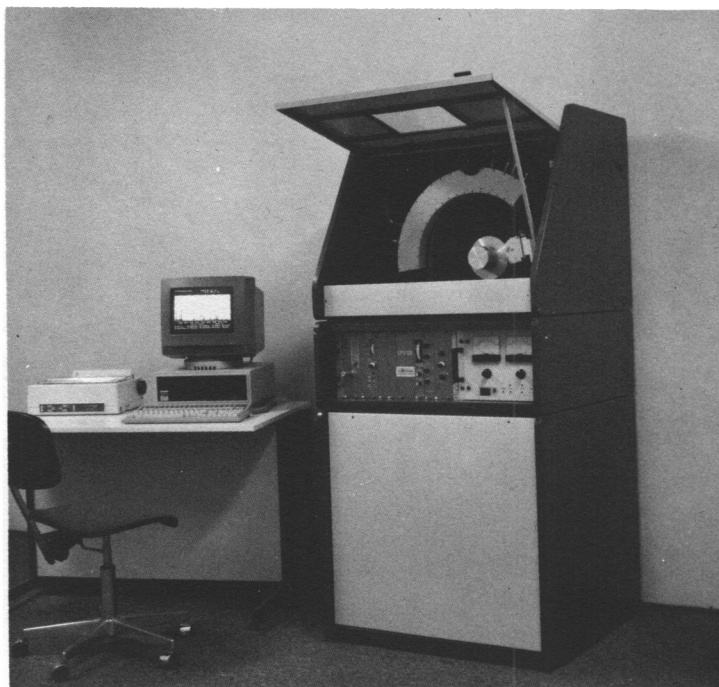
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matches
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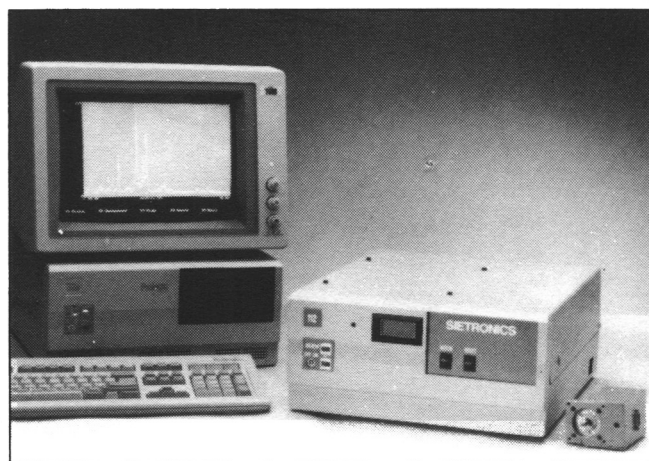
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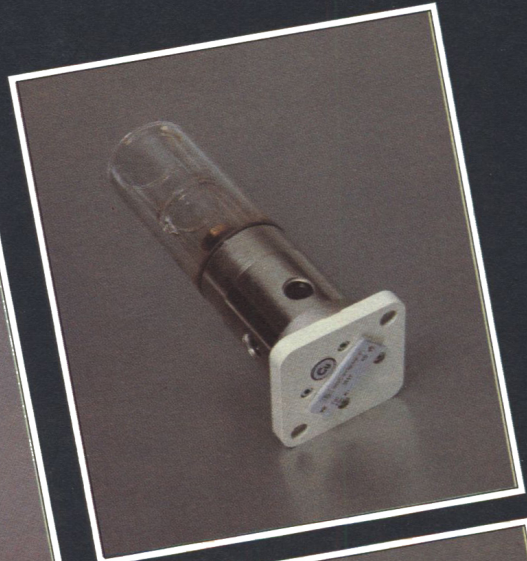
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Editorial

Editors for the Powder Diffraction File

The International Centre for Diffraction Data is seeking editors for data evaluation of the information to be included in the Powder Diffraction File. The PDF is the principal worldwide reference for powder diffraction information, and its value is primarily enhanced by the extensive review and checking of the data that is published. The responsibility for this data review is accomplished by experienced scientists who act as editors and work closely with the Editor-in-Chief of the Powder Diffraction File. The wide range of new compounds being described in the literature indicates the need for more specialists to review this information.

The editing of powder data involves reviewing the precision and accuracy of the primary experimental data with respect to the crystallographic information derived from the experimental data. The editing is also concerned with the correctness of the interpretation of the data by the author and the completeness of the descriptive supporting information from which the experimental data was obtained. Much of the review is assisted by a computer analyzed data evaluation which is prepared by the ICDD staff and supplied along with all the published information. The editor then makes recommendations on the disposition of the data, especially, whether to include it in a future issue of the PDF and whether to use it to replace previous data on the same material which might be already in the File. Editors also make recommendations to the ICDD Grants-in-Aid Program for areas of interest which need study.

The Board of Directors of ICDD has approved the hiring of several editors whose specialties cover fields in which powder data is used extensively. The goal of this search is to locate good editors with useful experience and cover as many fields as possible. This work is a paid service which can be done at one's own office anywhere in the world.

There is no need to be a member of the International Centre for Diffraction Data to apply. In fact, applications from Europe, Asia, Australia and other international regions are specifically encouraged.

Applications must be made in writing to:

Mr. Julian Messick, Secretary and General Manager
International Centre for Diffraction Data
1601 Park Lane
Swarthmore, PA 19081-2389 U.S.A.

Applications should include a complete vita and a description of a diffraction experience along with an indication of the types of compounds for which the applicant feels most qualified to review. Applications will be considered at any time up to 1 September 1989.

In addition to the openings for editors, there is an opening for an assistant Editor-in-Chief in the Headquarters office of the International Centre. This position will be responsible initially for coordinating the efforts of the outside editors and for the development of new data evaluation programs to assist the editors. This position is expected ultimately to assume the duties of the Editor-in-Chief. Applications for this position also should be sent to the above address.

Further information on these positions may be seen in the advertisement elsewhere in this issue.

Deane K. Smith
Chairman, International Centre
for Diffraction Data